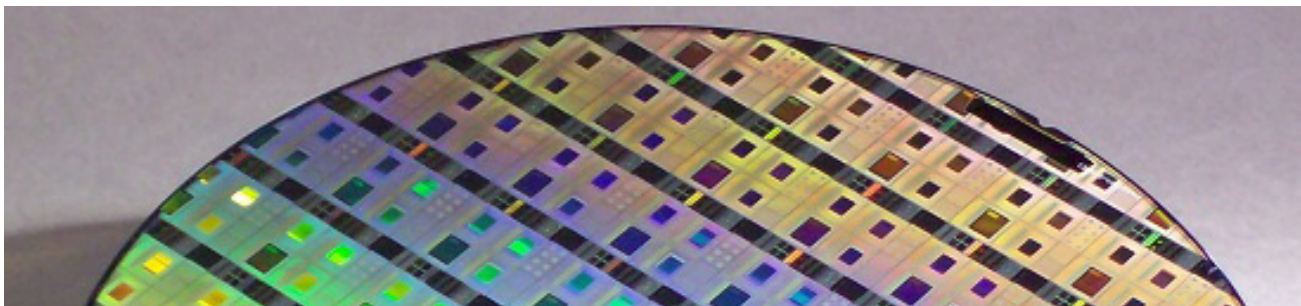




INTERFACES IN SEMICONDUCTORS

– building understanding across the scales

WORKSHOP

22nd - 23rd of October 2014
at Oslo Science Park

Day 1 – "Tutorial Day": Local scientists working on different aspects of semiconductor physics and materials characterization get together to exchange knowledge and build a common understanding of challenges and possibilities within the field.

Day 2 – "State-of-the-art Day": External guest speakers for further inspiration.

One of the aims of the workshop is to utilize the collective potential represented by the recent national infrastructure investments NORTEM, NICE and NorFab. See program for further details. The workshop is sponsored by NORTEM, SINTEF, UiO LENS and NFR.

All interested participants are most welcome!

Participant fee: NOK 500

Registration deadline: October 15th

[CLICK HERE TO REGISTER](#)

Organized by:
UiO Structure Physics
UiO Semiconductor Physics
SINTEF Materials Physics

When devices go
NANO interfaces
will be a big deal in
lots of stuff, right???

Indeed!
That's what
makes this topic
so interesting...



Joint Workshop on

Interfaces in semiconductors – building understanding across the scales

Wednesday Oct 22th - Tutorial day:

9.00-9.15	Welcome
9.15-10.00	Introduction to semiconductors and interfaces (K.M. Johansen, UiO)
10.15-11.00	Electrical characterization of semiconductors and interface states (L. Vines, UiO)
11.15-12.00	Ab initio calculations of semiconductors and interfaces (E. Flage-Larsen, SINTEF)
12.00-13.15	Lunch
13.15-14.00	Electron spectroscopy for interface investigations - possibilities and limitations using TEM, XPS and PL (Ø. Prytz, UiO / I.J.T Jensen, SINTEF / A. Galeckas, UiO)
14.15-15.00	Electron spectroscopy... (continued)
15.15-16.00	Characterization and modeling of interfaces and surfaces in solar cells (E. Marstein - IFE)
16.00-	Food and drinks

Thursday Oct 23rd - State-of-the-art day:

09.00-09.15	Welcome
09.15-10.00	NORTEM, NICE and NorFab: Infrastructure, activities and ambitions at UiO and SINTEF (Ø. Prytz, UiO / I.J.T. Jensen, SINTEF / A. Kuznetsov, UiO)
10.15-11.00	Surfaces and interfaces in electronic materials (L. Brillson, Ohio State University - USA)
11.15-12.00	Opportunities and challenges in local band gap measurements by VEELS: the case of CIGS solar cells (D. Keller, EMPA - Switzerland)
12.00-13.15	Lunch
13.15-14.00	The ever expanding photoemission toolbox: seeing beyond the surface (J. Wells – NTNU - Norway)
14.15-15.00	Transmission electron microscopy of semiconductors and oxides (W. Sigle, Max Planck Institute - Germany)
15.00-15.15	Closing remarks